

Special Interest Groups (SIGs)

Special Interest Groups are an outgrowth of the positive interactions promoted by the Workshop. While primarily originating with the discussion groups, SIGs can also originate independently.

SIG topics are simply those of common interest relating to the Workshop goals. While some SIGs are specific-goal-oriented (those with a specified target purpose i.e. solve a specific problem, perform a specific experiment), others have been set up to provide a focal point for information on new or emerging technologies (e.g. an informational SIG).

SIGs are encouraged to maintain contact throughout the year and continue activities whenever possible. Meeting and recruiting at other conferences is encouraged since the SIGs are viewed as an outgrowth of the Workshop, but not limited to its boundaries.

Membership and participation in SIGs is entirely voluntary. Often an interested individual will find several topics of interest.

Multiple memberships are possible.

To investigate membership in a particular SIG, contact the SIG leader for that topic. If you are interested in formation of a new SIG, please contact David Kirchner (dwk@smtmhs.sharpwa.com, 360-834-8777) for further information.

SIGs meeting at the 1995 IRW were:

<u>SIG</u>	<u>SIG Leader</u>
Electromigration	Marty Johnson - National Semiconductor 408-721-3077
WLR Implementation	Gordon Claudius - Rockwell gordon.claudius@nb.rockwell.com 714-833-4060
Thin Oxides	Cleston Messick - National Semiconductor ccrmsl@tevm2.nsc.com 801-562-7546
Hot Carriers	Eric Snyder - Sandia National Labs esnyder@sandia.gov 505-845-8577
ESD	Marty Frary - Storage Tek jmfrary@aol.com 303-673-7537
Mobile Ion	Mark Poulter - National Semiconductor cmwpsc@tevm2.nsc.com 408-721-8472
Test Chip Design	Harry Shafft - NIST schafft@apollo.eeel.nist.gov 301-975-2234
Package Reliability Test Chip Design	James Sweet - Sandia National Labs

	sweetjn@smtplink.mdl.sandia.gov 505-845-8242
Charge Monitor	Wes Lukaszek - Wafer Charging Monitors, Inc. lukaszek@aol.com 415-851-9313
Stress Migration	Jay Shideler - National Semiconductor 408-721-7558
Reliability Tools and Modeling	Ping-Chung Li - AMD pili@brahms.amd.com 408-749-6549
	and a new SIG on
Statistics	David Gibson - Gibson Engineering gibson@ujima.mirc.gatech.edu 404-329-8937
	Other existing SIGs include:
HAST	David Wilkie - Microchip Technology 602-963-7373
Thick Oxide Dielectric Integrity	David Huang - Cirrus Logic dhuang@corp.cirrus.com 510-623-8300
Wafer Level/Die Level Burn-in	David Kirchner - Sharp Microelectronics dwk@smtmhs.sharpwa.com 360-834-8777
Latchup	(no SIG leader identified)
Spin-on Glass	Mark Poulter - National Semiconductor cmwpssc@tevm2.nsc.com